



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: F1206-01 Product Affected: 80HCPS1616 & 80HSPS1616 (Refer to Attachment I) Date Effective: November 3, 2012	DATE: August 3, 2012	MEANS OF DISTINGUISHING CHANGED DEVICES: <input checked="" type="checkbox"/> Product Mark Change in Ordering Part Number <input type="checkbox"/> Back Mark <input type="checkbox"/> Date Code <input type="checkbox"/> Other
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Contact: Mary Vesey Title: Director, Product Assurance Phone #: (408) 284-4565 Fax #: (408) 284-1450 E-mail: mary.vesey@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Samples are available now.
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DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input checked="" type="checkbox"/> Other - Die Revision Change	<p>This notification is to advise our customers that IDT has qualified a new die revision C to correct the functional errata. There will be a change in ordering part number and device top mark.</p> <p>There is no change in die technology/process.</p> <p>Please see attachment for details.</p>
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RELIABILITY/QUALIFICATION SUMMARY:
See attached data. There is no change in die technology/process.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:
 IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
 IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone # /Fax #: _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT I - PCN #: F1206-01

PCN Type: Die Revision Change

Data Sheet Change: Yes

Detail of Change:

This notification is to advise our customers that IDT has qualified a new die revision C to correct the functional errata. There will be a change in ordering part number and device top mark as shown in Table 1.

Table 1

Old Ordering Part Number	New Ordering Part Number	Old Ordering Part Number	New Ordering Part Number
80HCPS1616RM	80HCPS1616CRM	80HSPS1616RM	80HSPS1616CRM
80HCPS1616RM8	80HCPS1616CRM8	80HSPS1616RM8	80HSPS1616CRM8
80HCPS1616RMI	80HCPS1616CRMI	80HSPS1616RMI	80HSPS1616CRMI
80HCPS1616RMI8	80HCPS1616CRMI8	80HSPS1616RMI8	80HSPS1616CRMI8

Qualification Test Plan and Result:

Qualification Plan #: QSM-1005-01R2
Qual Vehicle: 80HCPS1616

Test Description	Test Method (Latest specs in effect)	Test Results (SS / Rej)
Operating Lifestest (Dynamic) 125°C@1000 Hrs	JESD22-A108B	77/0, 77/0, 77/0
Temperature Humidity Bias 85°C/85%RH@1000 Hrs	JESD22-A101	25/0, 25/0, 25/0
Unbiased Highly Accelerated Stress Test 130°C/85%RH@100 Hrs	JESD22-A118	25/0, 25/0, 25/0
Temperature Cycle -55°C to 125°C@700 Cycles	JESD22-A104B	25/0, 25/0, 25/0
High Temperature Storage Bake 150°C@1000 Hrs	JESD22-A103B	25/0, 25/0, 25/0
ESD: Human Body Model @ 2000V	JESD22-A114F	3/0
ESD: Charged Device Model @ 500V	JESD22-101C	3/0
Latch-up	JESD78	6/0

Note: For UHAST, THB and Temperature Cycle, samples have been subjected to pre-conditioning per JESD22-A113D Level 4 flow.



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ATTACHMENT I - PCN #: F1206-01

Qualification Test Plan and Result:

Qualification Plan #: QSM-1005-01R2
Qual Vehicle: 80HSPS1616

Test Description	Test Method (Latest specs in effect)	Test Results (SS / Rej)
Operating Lifetest (Dynamic) 125°C@1000 Hrs	JESD22-A108B	77/0, 77/0, 77/0
Temperature Humidity Bias 85°C/85%RH@1000 Hrs	JESD22-A101	25/0, 25/0, 25/0
Unbiased Highly Accelerated Stress Test 130°C/85%RH@100 Hrs	JESD22-A118	25/0, 25/0, 25/0
Temperature Cycle -55°C to 125°C@700 Cycles	JESD22-A104B	25/0, 25/0, 25/0
High Temperature Storage Bake 150°C@1000 Hrs	JESD22-A103B	25/0, 25/0, 25/0
ESD: Human Body Model @ 2000V	JESD22-A114F	3/0
ESD: Charged Device Model @ 500V	JESD22-101C	3/0
Latch-up	JESD78	6/0

Note: For UHAST, THB and Temperature Cycle, samples have been subjected to pre-conditioning per JESD22-A113D Level 4 flow.